

Search Notes

Application/Control No.

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Examiner

Jacob Y. Choi

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	268, 319, 277, 280, 281, 311	10/26/2006	JC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
All Related Class/Subclass		10/26/2006	JC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass & Text Search Conducted by Examiner	10/26/2006	JC